









LM5112, LM5112-Q1

SNVS234C - SEPTEMBER 2004 - REVISED SEPTEMBER 2016

# LM5112, LM5112-Q1 Tiny 7-A MOSFET Gate Driver

# 1 Features

- LM5112-Q1 is Qualified for Automotive Applications
- AEC-Q100 Grade 1 Qualified
- Manufactured on an Automotive Grade Flow
- Compound CMOS and Bipolar Outputs Reduce
   Output Current Variation
- 7-A Sink and 3-A Source Current
- Fast Propagation Times: 25 ns (Typical)
- Fast Rise and Fall Times: 14 ns or 12 ns Rise or Fall With 2-nF Load
- Inverting and Non-Inverting Inputs Provide Either Configuration With a Single Device
- Supply Rail Undervoltage Lockout Protection
- Dedicated Input Ground (IN\_REF) for Split Supply or Single Supply Operation
- Power Enhanced 6-Pin WSON Package (3 mm × 3 mm) or Thermally Enhanced MSOP-PowerPAD Package
- Output Swings From V<sub>CC</sub> to V<sub>EE</sub> Which Are Negative Relative to Input Ground

# 2 Applications

Tools &

Software

- DC to DC Switch-Mode Power Supplies
- AC to DC Switch-Mode Power Supplies
- Solar Microinverters
- Solenoid and Motor Drives

# 3 Description

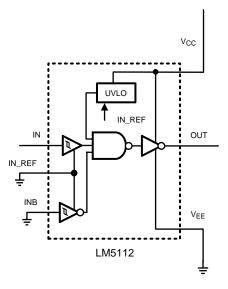
The LM5112 device MOSFET gate driver provides high peak gate drive current in the tiny 6-pin WSON package (SOT-23 equivalent footprint) or an 8-pin exposed-pad MSOP package with improved power dissipation required for high frequency operation. The compound output driver stage includes MOS and bipolar transistors operating in parallel that together sink more than 7 A peak from capacitive loads. Combining the unique characteristics of MOS and bipolar devices reduces drive current variation with voltage and temperature. Undervoltage lockout protection is provided to prevent damage to the MOSFET due to insufficient gate turnon voltage. The LM5112 device provides both inverting and noninverting inputs to satisfy requirements for inverting and non-inverting gate drive with a single device type.

## Device Information<sup>(1)</sup>

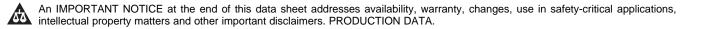
PART NUMBER	PACKAGE	BODY SIZE (NOM)
LM5112,	WSON (6)	3.00 mm × 3.00 mm
LM5112-Q1	MSOP PowerPAD (8)	3.00 mm × 3.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

## Simplified Block Diagram



Copyright © 2016, Texas Instruments Incorporated



# **Table of Contents**

1	Feat	tures	1				
2	Applications 1						
3	Description 1						
4	Rev	ision History	2				
5	Pin	Configuration and Functions	3				
6	Spe	cifications	4				
	6.1	Absolute Maximum Ratings	4				
	6.2	ESD Ratings	4				
	6.3	Recommended Operating Conditions	4				
	6.4	Thermal Information	4				
	6.5	Electrical Characteristics	5				
	6.6	Switching Characteristics					
	6.7	Typical Characteristics	6				
7	Deta	ailed Description	8				
	7.1	Overview	8				
	7.2	Functional Block Diagram	8				
	7.3	Feature Description	9				

	7.4	Device Functional Modes	10
8	Арр	lication and Implementation	11
	8.1	Application Information	11
	8.2	Typical Application	11
9	Pow	er Supply Recommendations	13
10	Lay	out	13
	10.1	Layout Guidelines	13
	10.2	Layout Example	15
11	Dev	ice and Documentation Support	16
	11.1	Related Links	16
	11.2	Receiving Notification of Documentation Updates	16
	11.3	Community Resources	16
	11.4	Trademarks	16
	11.5		
	11.6	Glossary	16
12		hanical, Packaging, and Orderable mation	16

# **4** Revision History

•

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

#### Changes from Revision B (April 2006) to Revision C

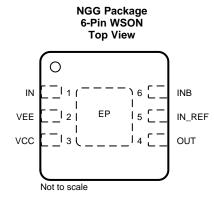
Added ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation	
section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and	
Mechanical, Packaging, and Orderable Information section	1
Changed values in the Thermal Information table to align with JEDEC standards	4

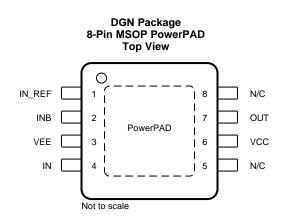
www.ti.com

Page



# 5 Pin Configuration and Functions





# **Pin Functions**

PIN		PIN		DESCRIPTION	
NAME	WSON	MSOP	I/O	DESCRIPTION	
Exposed Pad	_	_	—	Exposed pad, underside of package: Internally bonded to the die substrate. Connect to $V_{EE}$ ground pin for low thermal impedance.	
IN	1	4	I	Non-inverting input pin: TTL compatible thresholds. Pull up to $V_{CC}$ when not used.	
INB	6	2	I	Inverting input pin: TTL compatible thresholds. Connect to IN_REF when not used.	
IN_REF	5	1	_	Ground reference for control inputs: Connect to power ground ( $V_{EE}$ ) for standard positive only output voltage swing. Connect to system logic ground when $V_{EE}$ is connected to a negative gate drive supply.	
N/C	_	5, 8	_	Not internally connected	
OUT	4	7	0	Gate drive output: Capable of sourcing 3 A and sinking 7 A. Voltage swing of this output is from $V_{\text{EE}}$ to $V_{\text{CC}}.$	
V <sub>CC</sub>	3	6	I	Positive supply voltage input: Locally decouple to $V_{\text{EE}}$ . The decoupling capacitor must be placed close to the chip.	
V <sub>EE</sub>	2	3	_	Power ground for driver outputs: Connect to either power ground or a negative gate drive supply for positive or negative voltage swing.	

#### LM5112, LM5112-Q1

TEXAS INSTRUMENTS

www.ti.com

# 6 Specifications

#### 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)(2)</sup>

	MIN	MAX	UNIT
V <sub>CC</sub> to V <sub>EE</sub>	-0.3	15	V
V <sub>CC</sub> to IN_REF	-0.3	15	V
IN/INB to IN_REF	-0.3	15	V
IN_REF to V <sub>EE</sub>	-0.3	5	V
Maximum junction temperature		150	°C
Operating junction temperature	-40	125	°C
Storage temperature, T <sub>stg</sub>	-55	150	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) If Military/Aerospace specified devices are required, please contact the Texas Instruments Sales Office/ Distributors for availability and specifications.

#### 6.2 ESD Ratings

			VALUE	UNIT
V <sub>(ESD)</sub>	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±2000	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

#### 6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V <sub>CC</sub>	Operating voltage, $V_{CC}$ – IN_REF and $V_{CC}$ – $V_{EE}$	3.5	14	V
	Operating junction temperature	-40	125	°C

#### 6.4 Thermal Information

		LM51	LM5112, LM5112-Q1			
	THERMAL METRIC <sup>(1)</sup>	NGG (WSON)	DGN (MSOP PowerPAD)	UNIT		
		6 PINS	8 PINS			
$R_{\thetaJA}$	Junction-to-ambient thermal resistance	40	53.7	°C/W		
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	50.8	61.1	°C/W		
$R_{\theta JB}$	Junction-to-board thermal resistance	29.3	37.2	°C/W		
ΨJT	Junction-to-top characterization parameter	0.7	7.2	°C/W		
Ψјв	Junction-to-board characterization parameter	29.5	36.9	°C/W		
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	7.5	4.7	°C/W		

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



#### 6.5 Electrical Characteristics

 $T_J = -40^{\circ}C$  to 125°C,  $V_{CC} = 12$  V, INB = IN\_REF =  $V_{EE} = 0$  V, and no Load on output (unless otherwise noted).

	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY					·	
V <sub>CC</sub>	Operating voltage	$V_{CC}$ – IN_REF and $V_{CC}$ – $V_{EE}$	3.5		14	V
UVLO	Undervoltage lockout (rising)	V <sub>CC</sub> – IN_REF	2.4	3	3.5	V
V <sub>CCH</sub>	Undervoltage hysteresis			230		mV
I <sub>CC</sub>	Supply current			1	2	mA
CONTRO	L INPUTS					
V <sub>IH</sub>	Logic high		2.3			V
V <sub>IL</sub>	Logic low				0.8	V
V <sub>thH</sub>	High threshold		1.3	1.75	2.3	V
V <sub>thL</sub>	Low threshold		0.8	1.35	2	V
HYS	Input hysteresis			400		mV
IIL	Input current low	IN = INB = 0 V	-1	0.1	1	μA
I <sub>IH</sub>	Input current high	$IN = INB = V_{CC}$	-1	0.1	1	μΑ
OUTPUT	DRIVER					
R <sub>OH</sub>	Output resistance high	$I_{OUT} = -10 \text{ mA}^{(1)}$		30	50	Ω
R <sub>OL</sub>	Output resistance low	$I_{OUT} = 10 \text{ mA}^{(1)}$		1.4	2.5	Ω
ISOURCE	Peak source current	OUT = V <sub>CC</sub> / 2,200 ns pulsed current		3		А
I <sub>SINK</sub>	Peak sink current	OUT = V <sub>CC</sub> / 2,200 ns pulsed current		7		А
LATCHU	PROTECTION		·			
	AEC-Q100, METHOD 004	T <sub>J</sub> = 150°C		500		mA

(1) The output resistance specification applies to the MOS device only. The total output current capability is the sum of the MOS and bipolar devices.

# 6.6 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
td1	Propagation delay time low to high, IN or INB rising (IN to OUT)	C <sub>LOAD</sub> = 2 nF, see Figure 13		25	40	ns
td2	Propagation delay time high to low, IN or INB falling (IN to OUT)	C <sub>LOAD</sub> = 2 nF, see Figure 13		25	40	ns
tr	Rise time	C <sub>LOAD</sub> = 2 nF, see Figure 13		14		ns
tf	Fall time	C <sub>LOAD</sub> = 2 nF, see Figure 13		12		ns

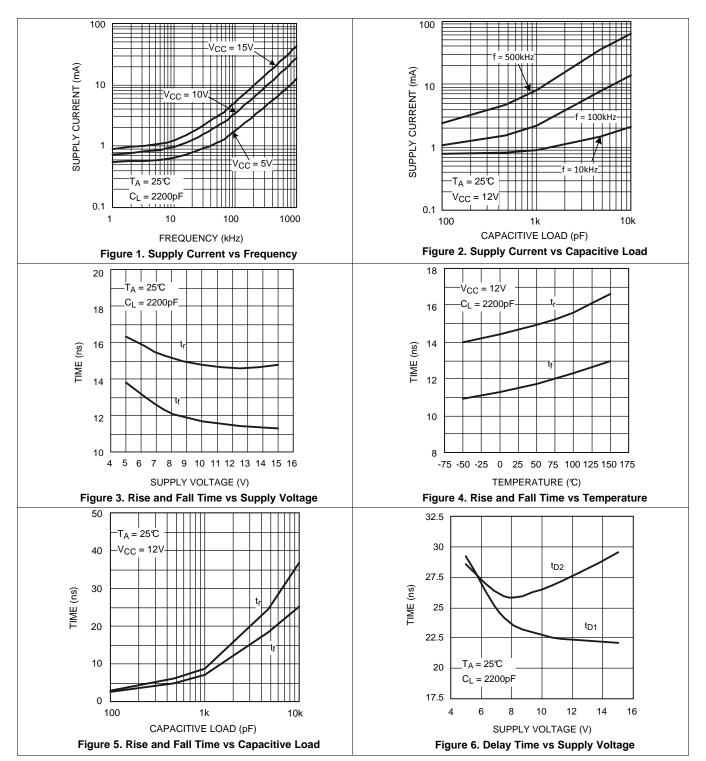
LM5112, LM5112-Q1

SNVS234C-SEPTEMBER 2004-REVISED SEPTEMBER 2016

TEXAS INSTRUMENTS

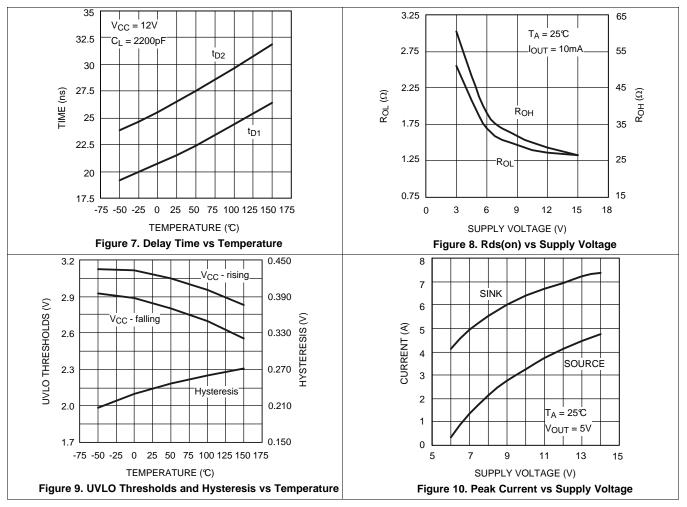
www.ti.com

# 6.7 Typical Characteristics





#### **Typical Characteristics (continued)**



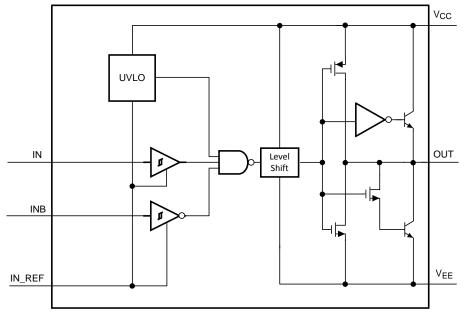


# 7 Detailed Description

# 7.1 Overview

The LM5112 device is a high-speed, high-peak current (7 A) single-channel MOSFET driver. The high-peak output current of the LM5112 device switches power MOSFETs on and off with short rise and fall times, thereby reducing switching losses considerably. The LM5112 device includes both inverting and non-inverting inputs that give the user flexibility to drive the MOSFET with either active low or active high logic signals. The driver output stage consists of a compound structure with MOS and bipolar transistor operating in parallel to optimize current capability over a wide output voltage and operating temperature range. The bipolar device provides high peak current at the critical Miller plateau region of the MOSFET V<sub>GS</sub>, while the MOS device provides rail-to-rail output swing. The totem pole output drives the MOSFET gate between the gate drive supply voltage V<sub>CC</sub> and the power ground potential at the V<sub>EE</sub> pin.

# 7.2 Functional Block Diagram



Copyright © 2016, Texas Instruments Incorporated

Figure 11. LM5112 Functional Block Diagram

8



## LM5112, LM5112-Q1 SNVS234C-SEPTEMBER 2004-REVISED SEPTEMBER 2016

# 7.3 Feature Description

The control inputs of the driver are high impedance CMOS buffers with TTL compatible threshold voltages. The negative supply of the input buffer is connected to the input ground pin IN\_REF. An internal level shifting circuit connects the logic input buffers to the totem pole output drivers. The level shift circuit and the separate input or output ground pins provide the option of single supply or split supply configurations. When driving the MOSFET gate from a single positive supply, the IN\_REF and  $V_{EE}$  pins are both connected to the power ground.

The isolated input and output stage grounds provide the capability to drive the MOSFET to a negative  $V_{GS}$  voltage for a more robust and reliable off state. In split supply configuration, the IN\_REF pin is connected to the ground of the controller which drives the LM5112 inputs. The  $V_{EE}$  pin is connected to a negative bias supply that can range from the IN\_REF potential to as low as 14 V below the  $V_{CC}$  gate drive supply. For reliable operation, the maximum voltage difference between  $V_{CC}$  and IN\_REF or between  $V_{CC}$  and  $V_{EE}$  is 14 V.

The minimum recommended operating voltage between  $V_{CC}$  and IN\_REF is 3.5 V. An undervoltage lockout (UVLO) circuit is included in the LM5112 which senses the voltage difference between  $V_{CC}$  and the input ground pin, IN\_REF. When the  $V_{CC}$  to IN\_REF voltage difference falls below 2.8 V the driver is disabled and the output pin is held in the low state. The UVLO hysteresis prevents chattering during brown-out conditions; the driver resumes normal operation when the  $V_{CC}$  to IN\_REF differential voltage exceeds 3 V.

#### 7.4 Device Functional Modes

The device output state is dependent on states of the IN and INB pins. Table 1 lists the output states for different input pin combinations.

0				
IN PIN	INB PIN	OUT PIN		
L	L	L		
L	Н	L		
Н	L	Н		
Н	Н	L		

#### Table 1. Device Logic Table

#### 7.4.1 Inverting Mode

During the inverting mode of operation, INB is used as the control input and the polarity of OUT is reversed with respect to INB. Figure 12 shows a timing diagram of this mode. The IN pin is not used in this mode of operation and must be pulled up to  $V_{CC}$ .

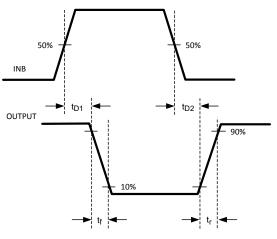


Figure 12. Inverting

#### 7.4.2 Non-Inverting Mode

During the non-inverting mode of operation, IN is used as the control input and the polarity of OUT is the same with respect to IN. Figure 13 shows a timing diagram of this mode. The INB pin is not used in this mode of operation and must be connected to IN\_REF.

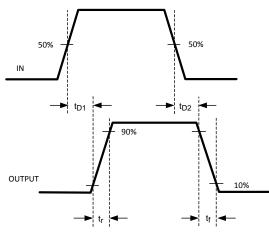


Figure 13. Non-Inverting



# 8 Application and Implementation

#### NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

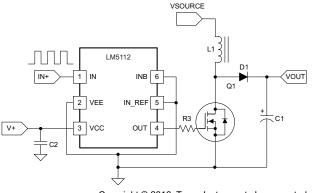
## 8.1 Application Information

A leading application for gate drivers such as the LM5112 is providing a high power buffer stage between the PWM output of a control IC and the gates of the primary power switching devices. In other cases, the driver IC is used to drive the power device gates through a drive transformer. Driver ICs are used when it is not feasible to have the primary PWM regulator IC directly drive the switching devices for one or more reasons. The PWM IC may not have the brute drive capability required for the intended switching MOSFET, limiting the switching performance in the application.

The LM5112 is used to drive a low side MOSFET with low switching losses. Either one of the control input pins, IN or INB, are used to control the gate drive to the MOSFET. The choice of the control input pin used depends on the polarity of operation.

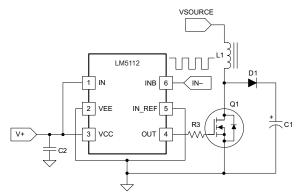
# 8.2 Typical Application

Typical application diagrams for the LM5112 device are shown below, illustrating use in non-inverting and inverting driver configurations. The high peak gate drive current of the LM5112 allows for short rise and fall times on the low-side MOSFET, thereby improving overall efficiency of the system and reducing switching losses.



Copyright © 2016, Texas Instruments Incorporated

## Figure 14. Typical Application Diagram (Using Non-Inverting Control Input)



Copyright © 2016, Texas Instruments Incorporated

#### Figure 15. Typical Application Diagram (Using Inverting Control Input)



## Typical Application (continued)

#### 8.2.1 Design Requirements

When selecting the proper gate driver device for an end application, some design considerations must be evaluated first to make the most appropriate selection. Among these considerations are input-to-output configuration, the input threshold type, bias supply voltage levels, peak source and sink currents, capacitive load, and switching frequency. Table 2 shows some sample values for a typical application.

PARAMETER	VALUE					
Input-to-output logic	Non-inverting					
$V_{CC}$ bias supply voltage (measured with respect to $V_{\text{EE}})$	12 V					
Supply configuration	Split supply					
Peak source current	3 A					
Peak sink current	7 A					
Output load (MOSFET gate capacitance)	2 nF					
Gate drive resistor	1 Ω					
Switching frequency	300 kHz					

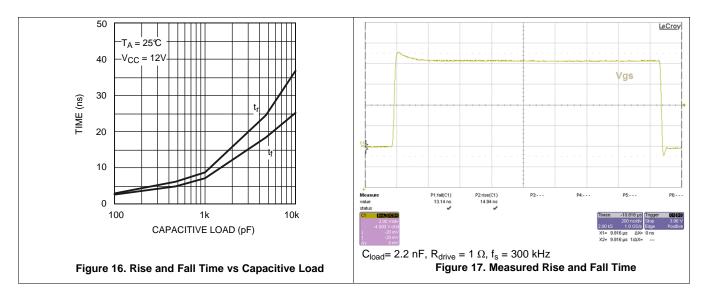
#### **Table 2. Design Parameters**

#### 8.2.2 Detailed Design Procedure

See *Power Supply Recommendations*, *Layout*, and *Thermal Considerations* for key design considerations regarding the input supply, grounding, and thermal calculations specific to the LM5112.

#### 8.2.3 Application Curves

The rise and fall times of the OUT signal depends on the capacitance of the MOSFET gate. Therefore, an appropriate MOSFET must be selected to meet the switching speed and efficiency requirements of the system. Figure 16 shows the rise and fall time curves as a function of capacitive load. Figure 17 shows output rise and fall time measured on an application board, showing actual device performance. The testing conditions for this figure are  $C_{load}$ = 2.2 nF,  $R_{drive}$  = 1  $\Omega$ , and  $f_s$  = 300 kHz.





# 9 Power Supply Recommendations

The recommended bias supply voltage range for LM5112 is from 3.5 V to 14 V. The lower end of this range is governed by the internal UVLO protection feature of the  $V_{CC}$  supply circuit. The upper end of this range is driven by the 14 V maximum recommended operating voltage rating of the  $V_{CC}$  supply. It is recommended to keep proper margin to allow for transient voltage spikes. The dedicated input ground pin (IN\_REF) allows split output supply operation. For such applications, ensure  $V_{EE}$  is not connected to IN\_REF.

The UVLO protection feature also involves a hysteresis function. This means that once the device is operating in normal mode, if the  $V_{CC}$  voltage drops, the device continues to operate in normal mode as long as the voltage drop does not exceed the hysteresis specification,  $V_{CCH}$ . If the voltage drop is greater than the hysteresis specification, the device shuts down. Therefore, while operating at or near the 3.5 V range, the voltage ripple on the auxiliary power supply output must be smaller than the hysteresis specification of LM5112 to avoid triggering device-shutdown.

A low-ESR or low-ESL capacitor must be connected close to the IC and between the  $V_{CC}$  and  $V_{EE}$  pins to support high peak currents being drawn from  $V_{CC}$  during turnon of the MOSFET. Also, if input pin (IN or INB) is not being used, it must be connected to  $V_{CC}$  or IN\_REF, respectively, to avoid spurious output signals.

# 10 Layout

## 10.1 Layout Guidelines

Attention must be given to board layout when using the LM5112 device. Some important considerations include:

Proper grounding is crucial. The driver required a low impedance path for current return to ground avoiding inductive loops. Two paths for returning current to ground are a) between the LM5112 device IN\_REF pin and the ground of the circuit that controls the driver inputs and b) between the LM5112 device  $V_{EE}$  pin and the source of the power MOSFET being driven. Both paths must be as short as possible to reduce inductance and be as wide as possible to reduce resistance. These ground paths must be distinctly separate to avoid coupling between the high current output paths and the logic signals that drive the LM5112 device. With rise and fall times in the range of 10 nsec to 30 nsec, care is required to minimize the lengths of current carrying conductors to reduce their inductance and EMI from the high di/dt transients generated when driving large capacitive loads.

## **10.1.1** Thermal Considerations

The primary goal of the thermal management is to maintain the integrated circuit (IC) junction temperature ( $T_J$ ) below a specified limit to ensure reliable long term operation. The maximum  $T_J$  of IC components must be estimated in worst case operating conditions. The junction temperature is calculated based on the power dissipated on the IC and the junction to ambient thermal resistance  $R_{\theta JA}$  for the IC package in the application board and environment. The  $R_{\theta JA}$  is not a given constant for the package and depends on the PCB design and the operating environment.

Layout Guidelines (continued)

# 10.1.1.1 Drive Power Requirement Calculations In LM5112

The LM5112 device is a single, low-side MOSFET driver capable of sourcing and sinking 3-A or 7-A peak currents for short intervals to drive a MOSFET without exceeding package power dissipation limits. High peak currents are required to switch the MOSFET gate quickly for operation at high frequencies.



Figure 18 shows a conceptual diagram of the LM5112 device output and MOSFET load. Q1 and Q2 are the switches within the gate driver.  $R_G$  is the gate resistance of the external MOSFET, and Cin is the equivalent gate capacitance of the MOSFET. The equivalent gate capacitance is a difficult parameter to measure as it is the combination of  $C_{GD}$  (gate to source capacitance) and  $C_{GD}$  (gate to drain capacitance). The  $C_{GD}$  is not a constant and varies with the drain voltage. The better way of quantifying gate capacitance is the gate charge  $Q_G$  in coloumbs.  $Q_G$  combines the charge required by  $C_{GD}$  and  $C_{GD}$  for a given gate drive voltage  $V_{GATE}$ . The gate resistance  $R_G$  is usually small and losses in it are neglected. The total power dissipated in the MOSFET driver due to gate charge is approximated by Equation 1.

$$\mathsf{P}_{\mathsf{DRIVER}} = \mathsf{V}_{\mathsf{GATE}} \times \mathsf{Q}_{\mathsf{G}} \times \mathsf{F}_{\mathsf{SW}}$$

where

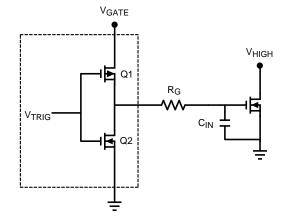
F<sub>SW</sub> = switching frequency of the MOSFET

For example, consider the MOSFET MTD6N15 whose gate charge specified as 30 nC for  $V_{GATE}$  = 12 V.

Therefore, the power dissipation in the driver due to charging and discharging of MOSFET gate capacitances at switching frequency of 300 kHz and  $V_{GATE}$  of 12 V is equal to Equation 2.

P<sub>DRIVER</sub> = 12 V × 30 nC × 300 kHz = 0.108 W

In addition to the above gate charge power dissipation, - transient power is dissipated in the driver during output transitions. When either output of the LM5112 device changes state, current flows from  $V_{CC}$  to  $V_{EE}$  for a brief interval of time through the output totem-pole N and P channel MOSFETs. The final component of power dissipation in the driver is the power associated with the quiescent bias current consumed by the driver input stage and Undervoltage lockout sections.



(1)

(2)



#### LM5112, LM5112-Q1 SNVS234C – SEPTEMBER 2004 – REVISED SEPTEMBER 2016

(6)

www.ti.com

#### Layout Guidelines (continued)

Characterization of the LM5112 device provides accurate estimates of the transient and quiescent power dissipation components. At 300 kHz switching frequency and 30 nC load used in the example, the transient power is 8 mW. The 1 mA nominal quiescent current and 12 V  $V_{GATE}$  supply produce a 12 mW typical quiescent power.

Therefore, the total power dissipation is calculated with Equation 3.	
$P_{D} = 0.118 + 0.008 + 0.012 = 0.138 W$	(3)
The junction temperature is given by Equation 4.	
$T_J = P_D \times R_{\theta JA} + T_A$	(4)

Or the rise in temperature is given by Equation 5.

$$T_{RISE} = T_{J} - T_{A} = P_{D} \times R_{\theta JA}$$
(5)

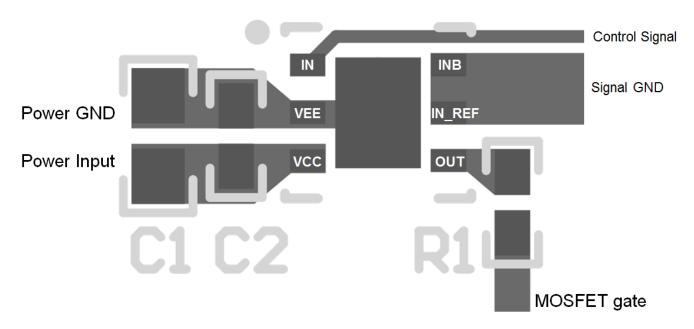
For 6-pin WSON package, the integrated circuit die is attached to leadframe die pad which is soldered directly to the printed circuit board. This substantially decreases the junction to ambient thermal resistance ( $R_{\theta JA}$ ). By providing suitable means of heat dispersion from the IC to the ambient through exposed copper pad, which can readily dissipate heat to the surroundings,  $R_{\theta JA}$  as low as 40°C/W is achievable with the package. The resulting  $T_{RISE}$  for the driver example above is thereby reduced to just 5.5°C.

Therefore,  $T_{RISE}$  is equal to Equation 6.

 $T_{RISE} = 0.138 \times 40 = 5.5^{\circ}C$ 

For MSOP-PowerPAD,  $R_{\theta JA}$  is typically 60°C/W.

# 10.2 Layout Example





11.1 Related Links

PARTS

LM5112

LM5112-Q1

11 Device and Documentation Support

resources, tools and software, and quick access to sample or buy.

11.2 Receiving Notification of Documentation Updates

PRODUCT FOLDER

Click here

Click here

11.3 Community Resources The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on Alert me to register and receive a weekly digest of any product information that has

TI E2E<sup>™</sup> Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support TI's Design Support Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 11.4 Trademarks

E2E is a trademark of Texas Instruments. All other trademarks are the property of their respective owners.

#### 11.5 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### 11.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

# 12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Copyright © 2004–2016, Texas Instruments Incorporated

#### Table 3. Related Links

**SAMPLE & BUY** 

Click here

Click here

changed. For change details, review the revision history included in any revised document.

**TECHNICAL** 

DOCUMENTS

Click here

Click here

**TOOLS &** 

SOFTWARE

Click here

Click here

The table below lists quick access links. Categories include technical documents, support and community

ISTRUMENTS

FXAS

**SUPPORT &** 

COMMUNITY

Click here

Click here



# PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
	(1)		j		,	(2)	(6)	(3)		(4.5)	
LM5112MY/NOPB	ACTIVE	HVSSOP	DGN	8	1000	RoHS & Green	SN	Level-1-260C-UNLIM		SJJB	Samples
LM5112MYX/NOPB	ACTIVE	HVSSOP	DGN	8	3500	RoHS & Green	SN	Level-1-260C-UNLIM		SJJB	Samples
LM5112Q1SD/NOPB	ACTIVE	WSON	NGG	6	1000	RoHS & Green	SN	Level-1-260C-UNLIM	-40 to 125	L250B	Samples
LM5112Q1SDX/NOPB	ACTIVE	WSON	NGG	6	4500	RoHS & Green	SN	Level-1-260C-UNLIM	-40 to 125	L250B	Samples
LM5112SD	LIFEBUY	WSON	NGG	6	1000	Non-RoHS & Green	Call TI	Level-1-260C-UNLIM	-40 to 125	L132B	
LM5112SD/NOPB	ACTIVE	WSON	NGG	6	1000	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 125	L132B	Samples
LM5112SDX/NOPB	ACTIVE	WSON	NGG	6	4500	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 125	L132B	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.



# PACKAGE OPTION ADDENDUM

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:**The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF LM5112, LM5112-Q1 :

• Catalog : LM5112

• Automotive : LM5112-Q1

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects



Texas

STRUMENTS

# TAPE AND REEL INFORMATION





#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM5112MY/NOPB	HVSSOP	DGN	8	1000	178.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
LM5112MYX/NOPB	HVSSOP	DGN	8	3500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
LM5112Q1SD/NOPB	WSON	NGG	6	1000	178.0	12.4	3.3	3.3	1.0	8.0	12.0	Q1
LM5112Q1SDX/NOPB	WSON	NGG	6	4500	330.0	12.4	3.3	3.3	1.0	8.0	12.0	Q1
LM5112SD	WSON	NGG	6	1000	178.0	12.4	3.3	3.3	1.0	8.0	12.0	Q1
LM5112SD/NOPB	WSON	NGG	6	1000	180.0	12.4	3.3	3.3	1.0	8.0	12.0	Q1
LM5112SD/NOPB	WSON	NGG	6	1000	178.0	12.4	3.3	3.3	1.0	8.0	12.0	Q1
LM5112SDX/NOPB	WSON	NGG	6	4500	330.0	12.4	3.3	3.3	1.0	8.0	12.0	Q1



# PACKAGE MATERIALS INFORMATION

12-Sep-2023



All ultrensions are norminal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LM5112MY/NOPB	HVSSOP	DGN	8	1000	208.0	191.0	35.0
LM5112MYX/NOPB	HVSSOP	DGN	8	3500	367.0	367.0	35.0
LM5112Q1SD/NOPB	WSON	NGG	6	1000	208.0	191.0	35.0
LM5112Q1SDX/NOPB	WSON	NGG	6	4500	367.0	367.0	35.0
LM5112SD	WSON	NGG	6	1000	208.0	191.0	35.0
LM5112SD/NOPB	WSON	NGG	6	1000	200.0	183.0	25.0
LM5112SD/NOPB	WSON	NGG	6	1000	208.0	191.0	35.0
LM5112SDX/NOPB	WSON	NGG	6	4500	367.0	367.0	35.0

# IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2023, Texas Instruments Incorporated